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Title:Terahertz time-domain spectroscopy characterization of vertically aligned carbon nanotube films

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Abstract:Terahertz time-domain spectroscopy measurements were made for vertically aligned multi-walled carbon nanotube (VACNT) films. We obtained the frequency dependent complex permittivity and conductivity (on the assumption that permeability μ=1) of several samples exhibiting Drude behaviour for lossy metals. The obtained material properties of VACNT films provide information for potential microwave and terahertz applications. [All rights reserved Elsevier].

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Inspec controlled terms:carbon nanotubes - electrical conductivity - permeability - permittivity - thin films

Uncontrolled terms:terahertz time-domain spectroscopy - vertically aligned carbon nanotube films - frequency dependent complex permittivity - electrical conductivity - permeability - Drude behaviour - C

Inspec classification codes:A7720 Dielectric permittivity - A6148 Structure of fullerenes and fullerene-related materials - A6855 Thin film growth, structure, and epitaxy - A7220F Low-field transport and mobility; piezoresistance (semiconductors/insulators)

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